Author index to volume 50

Barbet, J., A. Garvin, J. Thimonier, J.-P. Chauvin and J. Rocca-Serra, Scanning tunneling microscopy of colloidal gold beads 50 (1993) 355

Batson, P.E., Silicon $L_{2,3}$ near-edge fine structure in confined volumes 50 (1993) 1

Blanche, G., G. Hug, M. Jaouen and A.M. Flank, Comparison of the Ti K extended fine structure obtained from electron energy loss spectroscopy and X-ray absorption spectroscopy 50 (1993) 141

Chauvin, J.-P., see Barbet 50 (1993) 355

Cowley, J.M., see Gribelyuk 50 (1993) 29

Daberkow, I., K.-H. Herrmann and F. Lenz, A configurable angle-resolving detector system in STEM 50 (1993) 75

Dahmen, U., see Paciornik 50 (1993) 255

De Ruijter, W.J. and J.K. Weiss, Detection limits in quantitative off-axis electron holography 50 (1993) 269

De Ruijter, W.J., see Gajdardziska-Josifovska 50 (1993) 285

De Ruijter, W.J., see Weiss 50 (1993) 301

Egerton, R.F., Oscillator-strength parameterization of inner-shell cross sections 50 (1993) 13

Eibl, O., New method for absorption correction in high-accuracy, quantitative EDX microanalysis in the TEM including low-energy X-ray lines 50 (1993) 179

Eibl, O., Application of a new method for absorption correction in high-accuracy, quantitative EDX microanalysis in the TEM: analysis of oxygen in CuO-based high-T_c superconductors 50 (1993) 189

Eibl, O., Improved, parameterless, constant-current method for absorption correction in quantitative EDX microanalysis in the TEM 50 (1993) 203

Fink, H.-W., Comment on "On the electron and metallic ion emission from nanotips fabricated by field-surface-melting technique: experiments on W and Au tips" by Vu Thien Binh and N. García 50 (1993) 101

Flank, A.M., see Blanche 50 (1993) 141

Foitzik, A.H., J.S. Sears, S.-Q. Xiao and A.H. Heuer, On a high-purity Ge EDS detector. I. Determination of detector efficiency 50 (1993) 207

Foitzik, A.H., J.S. Sears, S.-Q. Xiao, A.H. Heuer and W. Wunderlich, On a high-purity Ge EDS detector. II. Ice layer formation and optimization of detector design 50 (1993) 219

Foitzik, A.H., S.-Q. Xiao, A.H. Heuer and W. Wunderlich, On a high-purity Ge EDS detector. III. The reliable acquisition of EDS spectra 50 (1993) 229

Gajdardziska-Josifovska, M., M.R. McCartney, W.J. de Ruijter, D.J. Smith, J.K. Weiss and J.M. Zuo, Accurate measurements of mean inner potential of crystal wedges using digital electron holograms 50 (1993) 285

Gajdardziska-Josifovska, M., see Weiss 50 (1993) 301

García, N., see Vu Thien Binh 50 (1993) 103

Garvin, A., see Barbet 50 (1993) 355

Gribelyuk, M.A. and J.M. Cowley, Determination of experimental imaging conditions for off-axis transmission electron holography 50 (1993) 29

Grunze, M., see Müller 50 (1993) 57

Hawkes, P.W., Proceedings, books and issues 50 (1993) 106

Herring, R.A., G. Pozzi, T. Tanji and A. Tonomura, Realization of a mixed type of interferometry using convergent-beam electron diffraction and an electron biprism 50 (1993) 94

Herrmann, K.-H., see Daberkow 50 (1993) 75

Heuer, A.H., see Foitzik 50 (1993) 207

Heuer, A.H., see Foitzik 50 (1993) 219

Heuer, A.H., see Foitzik 50 (1993) 229

Hirsch, P., M. Kässens, L. Reimer, R. Senkel and M. Spranck, Contrast of colloidal gold particles and thin films on a silicon substrate observed by backscattered electrons in a low-voltage scanning electron microscope 50 (1993) 263

Hofmann, M., see Müller 50 (1993) 57

Howe, J.M., see Rozeveld 50 (1993) 41

Hug, G., see Blanche 50 (1993) 141

Elsevier Science Publishers B.V.

Jäger, W., see Stenkamp 50 (1993) 321
Jaouen, M., see Blanche 50 (1993) 141

Kässens, M., see Hirsch 50 (1993) 263
Keller, D., see Luo 50 (1993) 147
Kilaas, R., see Paciornik 50 (1993) 255
Kruit, P., Editorial 50 (1993) vii
Kruit, P., Jan Bart Le Poole (1917–1993) 50 (1993) 121

Leapman, R.D., see Sun 50 (1993) 127
Lehmpfuhl, G., see Wang 50 (1993) 239
Lenz, F., see Daberkow 50 (1993) 75
Luo, K., M. Yorgancioglu and D. Keller, Scanning force microscopy at −25°C 50 (1993) 147

McCartney, M.R., see Gajdardziska-Josifovska 50 (1993) 285
McCartney, M.R., see Weiss 50 (1993) 301
Merli, P.G. and M. Nacucchi, Resolution of superlattice structures with backscattered electrons in a scanning electron microscope 50 (1993) 83
Midgley, P.A., see Vincent 50 (1993) 365
Müller, H.U., B. Völkel, M. Hofmann, Ch. Wöll and M. Grunze, Emission properties of electron point sources 50 (1993) 57

Nacucchi, M., see Merli 50 (1993) 83

Paciornik, S., R. Kilaas and U. Dahmen, Assessment of specimen noise in HREM images of simple structures 50 (1993) 255
Pozzi, G., see Herring 50 (1993) 94

Reimer, L., see Hirsch 50 (1993) 263
Reuter, M.C., see Tromp 50 (1993) 171
Rocca-Serra, J., see Barbet 50 (1993) 355
Rozeveld, S.J. and J.M. Howe, Determination of multiple lattice parameters from convergent-beam electron diffraction patterns 50 (1993) 41

Sears, J.S., see Foitzik 50 (1993) 207
Sears, J.S., see Foitzik 50 (1993) 219
Senkel, R., see Hirsch 50 (1993) 263
Shao, Z., see Yang 50 (1993) 157
Shi, S., see Sun 50 (1993) 127
Smith, D.J., see Gajdardziska-Josifovska 50 (1993) 285
Smith, D.J., see Weiss 50 (1993) 301
Spellward, P., see Vincent 50 (1993) 365
Spranck, M., see Hirsch 50 (1993) 263

Ge_{1-x} alloys and heterostructures by high-resolution transmission electron microscopy 50 (1993) 321
Sun, S., S. Shi and R.D. Leapman, Water distributions of hydrated biological specimens by valence electron energy loss spectroscopy 50 (1993) 127

Tanji, T., see Herring 50 (1993) 94
Thimonier, J., see Barbet 50 (1993) 355
Tochilin, S.B. and M.J. Whelan, Combined basis algorithm for HREM wave field calculations 50 (1993) 313
Tonomura, A., see Herring 50 (1993) 94
Tromp, R.M. and M.C. Reuter, Imaging with a low-energy electron microscope 50 (1993) 171
Tsuno, K., Resolution limit of a transmission electron microscope with an uncorrected conventional magnetic objective lens 50 (1993) 245

Uchida, Y., see Wang 50 (1993) 239

Vincent, R., W.J. Vine, P.A. Midgley, P. Spellward and J.W. Steeds, Coherent overlapping LACBED patterns in 6H SiC 50 (1993) 365
Vine, W.J., see Vincent 50 (1993) 365
Völkel, B., see Müller 50 (1993) 57
Vu Thien Binh and N. García, Reply to "Comment of H.-W. Fink on 'On the electron and metallic ion emission from nanotips fabricated by field-surface-melting technique: experiments on W and Au tips' by Vu Thien Binh and N. García" 50 (1993) 103

Wang, N., Y. Uchida and G. Lehmpfuhl, Contrast variation of Au(111) reconstructed surfaces with defocus in REM 50 (1993) 239
Weiss, J.K., see De Ruijter 50 (1993) 269
Weiss, J.K., see Gajdardziska-Josifovska 50 (1993) 285
Weiss, J.K., W.J. de Ruijter, M. Gajdardziska-Josifovska, M.R. McCartney and D.J. Smith, Applications of electron holography to the study of interfaces 50 (1993) 301
Weiss, K., see Zemlin 50 (1993) 123
Whelan, M.J., see Tochilin 50 (1993) 313
Wöll, Ch., see Müller 50 (1993) 57
Wunderlich, W., see Foitzik 50 (1993) 219
Wunderlich, W., see Foitzik 50 (1993) 229

Xiao, S.-Q., see Foitzik 50 (1993) 207
Xiao, S.-Q., see Foitzik 50 (1993) 219
Xiao, S.-Q., see Foitzik 50 (1993) 229

ited 50 (1993) 123
Zuo, J.M., see Gajdardziska-Josifovska 50 (1993) 285

Subject index to volume 50

Analytical microscopy

Compositional and structural characterization of Si_xGe_{1-x} alloys and heterostructures by high-resolution transmission electron microscopy, *Stenkamp and Jäger* 50 (1993) 321

Cross sections

Oscillator-strength parameterization of inner-shell cross sections, *Egerton* 50 (1993) 13

Contrast of colloidal gold particles and thin films on a silicon substrate observed by backscattered electrons in a low-voltage scanning electron microscope, *Hirsch, Kässens, Reimer, Senkel and Spranck* 50 (1993) 263

Detectors, photographic and other

A configurable angle-resolving detector system in STEM, *Daberkow, Herrmann and Lenz* 50 (1993) 75

Diffraction and optical diffraction

Determination of multiple lattice parameters from convergent-beam electron diffraction patterns, *Rozeveld and Howe* 50 (1993) 41

Robust real-space method for the calculation of fast electron forward scattering, *Hugsted* 50 (1993) 65

Resolution of superlattice structures with backscattered electrons in a scanning electron microscope, *Merli and Nacucchi* 50 (1993) 83

Realization of a mixed type of interferometry using convergent-beam electron diffraction and an electron biprism, *Hering, Pozzi, Tanji and Tonomura* 50 (1993) 94

Coherent overlapping LACBED patterns in 6H SiC, *Vincent, Vine, Midgley, Spellward and Steeds* 50 (1993) 365

Electron energy loss spectroscopy

Silicon $L_{2,3}$ near-edge fine structure in confined volumes, *Batson* 50 (1993) 1

Oscillator-strength parameterization of inner-shell cross sections, *Egerton* 50 (1993) 13

Water distributions of hydrated biological specimens by valence electron energy loss spectroscopy, *Sun, Shi and Leapman* 50 (1993) 127

Comparison of the Ti K extended fine structure obtained from electron energy loss spectroscopy and X-ray absorption spectroscopy, *Blanche, Hug, Jaouen and Flank* 50 (1993) 141

Electron probe microanalysis

New method for absorption correction in high-accuracy, quantitative EDX microanalysis in the TEM including low-energy X-ray lines, *Eibl* 50 (1993) 179

Application of a new method for absorption correction in high-accuracy, quantitative EDX microanalysis in the TEM: analysis of oxygen in CuO-based high-T_c superconductors, *Eibl* 50 (1993) 189

Improved, parameterless, constant-current method for absorption correction in quantitative EDX microanalysis in the TEM, *Eibl* 50 (1993) 203

On a high-purity Ge EDS detector. I. Determination of detector efficiency, *Foitzik, Sears, Xiao and Heuer* 50 (1993) 207

On a high-purity Ge EDS detector. II. Ice layer formation and optimization of detector design, *Foitzik, Sears, Xiao, Heuer and Wunderlich* 50 (1993) 219

On a high-purity Ge EDS detector. III. The reliable acquisition of EDS spectra, *Foitzik, Xiao, Heuer and Wunderlich* 50 (1993) 229

High resolution

Assessment of specimen noise in HREM images of simple structures, *Paciornik, Kilaas and Dahmen* 50 (1993) 255

Combined basis algorithm for HREM wave field calculations, *Tochilin and Whelan* 50 (1993) 313

Compositional and structural characterization of Si_xGe_{1-x} alloys and heterostructures by high-resolution transmission electron microscopy, *Stenkamp and Jäger* 50 (1993) 321

Holography

Determination of experimental imaging conditions for off-axis transmission electron holography, *Gribelyuk and Cowley* 50 (1993) 29

Detection limits in quantitative off-axis electron holography, *De Ruijter and Weiss* 50 (1993) 269

Elsevier Science Publishers B.V.

Weiss and Zuo 50 (1993) 285
Applications of electron holography to the study of interfaces, *Weiss, De Ruijter, Gajdardziska-Josifovska, McCartney and Smith* 50 (1993) 301

Image processing, 3D reconstruction
Young's interference fringes in electron microscopy revisited, *Zemlin and Weiss* 50 (1993) 123
Assessment of specimen noise in HREM images of simple structures, *Paciornik, Kilaas and Dahmen* 50 (1993) 255

Instrumentation
Emission properties of electron point sources, *Müller, Völkel, Hofmann, Wöll and Grunze* 50 (1993) 57

Low energy electron microscopy, photoemission microscopy
Imaging with a low-energy electron microscope, *Tromp and Reuter* 50 (1993) 171

Methods and techniques
Robust real-space method for the calculation of fast electron forward scattering, *Hugsted* 50 (1993) 65

New developments
Emission properties of electron point sources, *Müller, Völkel, Hofmann, Wöll and Grunze* 50 (1993) 57

Particle optics, theory
Resolution limit of a transmission electron microscope with an uncorrected conventional magnetic objective lens, *Tsuno* 50 (1993) 245

Reflection electron microscopy, reflection high-energy electron diffraction
Contrast variation of Au(111) reconstructed surfaces with defocus in REM, *Wang, Uchida and Lehmpfuhl* 50 (1993) 239

Scanning electron microscopy
Resolution of superlattice structures with backscattered electrons in a scanning electron microscope, *Merli and Nacucchi* 50 (1993) 83
Contrast of colloidal gold particles and thin films on a silicon substrate observed by backscattered electrons in a low-voltage scanning electron microscope, *Hirsch, Kässens, Reimer, Senkel and Spranck* 50 (1993) 263
field-surface-melting technique: experiments on W and Au tips" by Vu Thien Binh and N. García, *Fink* 50 (1993) 101
Reply to "Comment of H.-W. Fink on 'On the electron and metallic ion emission from nanotips fabricated by field-surface-melting technique: experiments on W and Au tips' by Vu Thien Binh and N. García", *Vu Thien Binh and García* 50 (1993) 103
Scanning force microscopy at −25°C, *Luo, Yorgancioglu and Keller* 50 (1993) 147
Effect of probe force on the resolution of atomic force microscopy of DNA, *Yang and Shao* 50 (1993) 157

Scanning transmission electron microscopy
Determination of experimental imaging conditions for off-axis transmission electron holography, *Gribelyuk and Cowley* 50 (1993) 29
A configurable angle-resolving detector system in STEM, *Daberkow, Herrmann and Lenz* 50 (1993) 75

Scanning tunneling microscopy
Scanning tunneling microscopy of colloidal gold beads, *Barbet, Garvin, Thimonier, Chauvin and Rocca-Serra* 50 (1993) 355

Spectrometers, auxiliary apparatus
On a high-purity Ge EDS detector. I. Determination of detector efficiency, *Foitzik, Sears, Xiao and Heuer* 50 (1993) 207
On a high-purity Ge EDS detector. II. Ice layer formation and optimization of detector design, *Foitzik, Sears, Xiao, Heuer and Wunderlich* 50 (1993) 219
On a high-purity Ge EDS detector. III. The reliable acquisition of EDS spectra, *Foitzik, Xiao, Heuer and Wunderlich* 50 (1993) 229

Surfaces, clusters, interfaces and particles
Silicon $L_{2,3}$ near-edge fine structure in confined volumes, *Batson* 50 (1993) 1
Oscillator-strength parameterization of inner-shell cross sections, *Egerton* 50 (1993) 13
Contrast of colloidal gold particles and thin films on a silicon substrate observed by backscattered electrons in a low-voltage scanning electron microscope, *Hirsch, Kässens, Reimer, Senkel and Spranck* 50 (1993) 263
Applications of electron holography to the study of interfaces, *Weiss, De Ruijter, Gajdardziska-Josifovska, McCartney and Smith* 50 (1993) 301